

CLAIMS

We claim:

1. A method comprising:

5 loading a device under test on a test site of a handler, the handler connected to a tester through a device under test board;

performing electrical tests on the device under test by operating the tester;

collecting results of the electrical test for individual sockets on the device under test board using the tester;

10 storing the electrical test results of the individual sockets on the device under test board in a storing unit of the tester and accumulating the results;

transmitting a part of the collected electrical test results to the handler and processing the device under test according to the received electrical test results;

15 comparing the accumulated electrical test results of the individual sockets on the device under test board to a reference value;

using the individual sockets on the device under test board based upon the comparison results; and

20 stopping use of a defective socket on the device under test board by transmitting the decision result to the handler.

2. The method of claim 1, wherein loading a device under test on a test site of a handler comprises loading the device under test on a horizontal type handler.

3. The method of claim 1, wherein the handler is operated by a first
25 microprocessor that is different from a second microprocessor that operates the tester.

4. The method of claim 1, wherein performing electrical tests comprises
simultaneously performing a parallel test for a plurality of devices under test mounted on the device under test board.

30 5. The method of claim 1, wherein loading a device under test comprises loading a memory device.

6. The method of claim 5, wherein loading a memory device comprises loading a dynamic random access memory (DRAM).

7. The method of claim 1, wherein collecting results of the electrical test for individual sockets comprises:
collecting continuity test results;
collecting leakage test results; and
collecting timing test results.

8. The method of claim 1, wherein transmitting a part of the collected electrical test results comprises transmitting sorting data for processing the devices under test after finishing the electrical test.

9. The method of claim 1, wherein comparing the electrical test results comprises comparing the electrical test results after a predetermined time has passed since the electrical test started.

10. The method of claim 1, wherein comparing the electrical test results comprises comparing the electrical test results after completing the electrical test for a predetermined number of devices under test.

11. The method of claim 1, wherein comparing the accumulated electrical test results to a reference value comprises comparing a number of defects in the continuity test to the reference value.

12. The method of claim 1, wherein comparing the accumulated electrical test results to a reference value comprises comparing a number of defects in the leakage test to the reference value.

13. The method of claim 1, wherein comparing the accumulated electrical test results to a reference value comprises comparing a number of defects in the timing test to the reference value.